

Test Report issued under the responsibility of:

SAMSUNG

TEST REPORT IEC 62471 Photobiological safety of lamps and lamp systems	
Report Reference No.	18-03-04
Date of issue	2018-03-20
Total number of pages	
Testing Laboratory	SAMSUNG ELECTRONICS Co., Ltd.
Address	1, Samsung-ro, Giheung-gu, Yongin-si, Gyeonggi-do, 17113, Korea
Applicant's name	SAMSUNG ELECTRONICS Co., Ltd.
Address	129, Samsung-ro, Yeongtong-gu, Suwon-si, Gyeonggi-do, 16677, Korea
Test specification:	
Standard	IEC 62471:2006 (First Edition)
Test procedure	N/A
Non-standard test method	N/A
Test Report Form No.	IEC62471A
TRF Originator	VDE Testing and Certification Institute
Master TRF	Dated 2009-05
Copyright © 2009 IEC System for Conformity Testing and Certification of Electrical Equipment (IECEE), Geneva, Switzerland. All rights reserved.	
This publication may be reproduced in whole or in part for non-commercial purposes as long as the IECEE is acknowledged as copy-right owner and source of the material. IECEE takes no responsibility for and will not assume liability for damages resulting from the reader's interpretation of the reproduced material due to its placement and context.	
If this Test Report Form is used by non-IECEE members, the IECEE/IEC logo and the reference to the CB Scheme procedure shall be removed.	
This report is not valid as a CB Test Report unless signed by an approved CB Testing Laboratory and appended to a CB Test Certificate issued by an NCB in accordance with IECEE 02.	
Test item description	LED PKG (LM561Bplus S6 rank)
Trade Mark	SAMSUNG
Manufacturer	Same as Testing Laboratory
Model/Type reference	SPMWHT541MP5WAP0S6
Ratings	DC 180 mA / 3,19 V

Testing procedure and testing location:	
<input type="checkbox"/> Testing Laboratory: Testing location/ address :	SAMSUNG ELECTRONICS Co., Ltd. (LED Biz.) 1, Samsung-ro, Giheung-gu, Yongin-si, Gyeonggi-do, 17113, Korea
<input type="checkbox"/> Associated Laboratory: Testing location/ address : Tested by (name + signature) : Approved by (+ signature) :	
<input type="checkbox"/> Testing procedure: TMP Tested by (name + signature) : Approved by (+ signature) : Testing location/ address :	
<input type="checkbox"/> Testing procedure: WMT Tested by (name + signature) : Witnessed by (+ signature) : Approved by (+ signature) : Testing location/ address :	
<input type="checkbox"/> Testing procedure: SMT Tested by (name + signature) : Approved by (+ signature) : Supervised by (+ signature) : Testing location/ address :	
<input type="checkbox"/> Testing procedure: RMT Tested by (name + signature) : Approved by (+ signature) : Supervised by (+ signature) : Testing location/ address :	

Summary of testing:**Tests performed (name of test and test clause):**

- The sample was applied DC 180 mA following by applicant request.
- The sample was measured at 25°C.

Testing location:

SAMSUNG ELECTRONICS Co., Ltd
1, Samsung-ro, Giheung-gu, Yongin-si,
Gyeonggi-do, 17113, Korea

Summary of compliance with National Differences:

The sample(s) tested complies with the requirements of IEC 62471:2006 and EN 62471:2008.
See Attachment at the end of this report for compliance with European Group Difference and National Differences.

Copy of marking plate:

Test item particulars:Tested lamp : ☒ continuous wave lamps ☐ pulsed lamps

Tested lamp system

Lamp classification group (IEC) : ☒ exempt ☐ risk 1 ☐ risk 2 ☐ risk 3Lamp classification group (EN) : ☐ exempt ☒ risk 1 ☐ risk 2 ☐ risk 3

Lamp cap

Bulb

Rated of the lamp : See Page 1

Furthermore marking on the lamp

Seasoning of lamps according IEC standard

Used measurement instrument.....

Temperature by measurement : 24.0 - 25.0 °C

Information for safety use..... : Not required

Possible test case verdicts:

- test case does not apply to the test object..... : N/A
- test object does meet the requirement..... : P (Pass)
- test object does not meet the requirement..... : F (Fail)

Testing:

Date of receipt of test item : 2018-03-08

Date (s) of performance of tests : 2018-03-09

General remarks:

The test results presented in this report relate only to the object tested.

This report shall not be reproduced, except in full, without the written approval of the Issuing testing laboratory.

"(See Enclosure #)" refers to additional information appended to the report.

"(See appended table)" refers to a table appended to the report.

Throughout this report a comma (point) is used as the decimal separator.

List of test equipment must be kept on file and available for review.

General product information:

- PKG : LM561Bplus
- CCT : 6500K
- CRI : 80
- Flux rank : S6
- Tested current : DC 180 mA
- A photo of test sample.



Throughout this report a ☒ comma / ☐ point is used as the decimal separator.